

Features

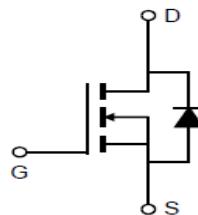
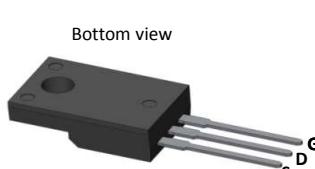
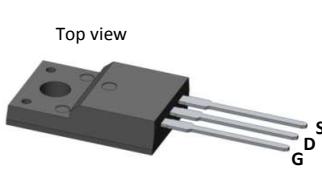
- CRM(CQ) Super_Junction technology
- Much lower Ron*A performance for On-state efficiency
- Better efficiency due to very low FOM

Product Summary

VDS	650V
R _{DS(on)} _typ	0.39Ω
I _D	11A

Applications

- LED/LCD/PDP TV and monitor Lighting
- Solar/Renewable/UPS-Micro Inverter System
- Charger
- Power Supply

100% DVDS Tested
100% Avalanche Tested

Package Marking and Ordering Information

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
CRJF390N65GC	CRJF390N65GC	TO220F	Tube	N/A	N/A	50pcs

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V _{DS}	650	V
Continuous drain current T _C = 25°C T _C = 100°C	I _D	11 7.0	A
Pulsed drain current (T _C = 25°C, t _p limited by T _{jmax})	I _D pulse	44	A
Avalanche energy, single pulse (L=60mH, R _g =30Ω)	E _{AS}	120	mJ
MOSFET dv/dt ruggedness	dv/dt	50	V/ns
Gate-Source voltage	V _{GS}	±30	V
Power dissipation (T _C = 25°C)	P _{tot}	29	W
Continuous diode forward current(T _C = 25°C)	I _S	11	A
Diode pulse current ²⁾ (T _C = 25°C)	I _S pulse	44	A
Recovery diode dv/dt ³⁾	dv/dt	50	V/ns
Operating junction and storage temperature	T _j , T _{stg}	-55...+150	°C

 1) Limited by T_{j,max}. Maximum Duty Cycle D = 0.50; TO-220 equivalent

 2) Pulse width t_p limited by T_{j,max}

3) Identical low side and high side switch with identical RG



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CRJF390N65GC

SJMOS N-MOSFET 650V, 0.39Ω, 11A

Thermal Resistance

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Thermal resistance, junction – case	R _{thJC}	-	3.07	4.30	°C/W	
Thermal resistance, junction – ambient	R _{thJA}	-	-	78	°C/W	

Electrical Characteristic (at T_j = 25 °C, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		

Static Characteristic

Drain-source breakdown voltage	BV _{DSS}	650	-	-	V	V _{GS} =0V, I _D =250μA
Gate threshold voltage	V _{GS(th)}	3.5	-	4.5	V	V _{DS} =V _{GS} , I _D =250μA
Zero gate voltage drain current	I _{DSS}	-	-	1	μA	V _{DS} =650V, V _{GS} =0V T _j =25°C T _j =150°C
Gate-source leakage current	I _{GSS}	-	0.3	80	nA	V _{GS} =±30V, V _{DS} =0V
Drain-source on-state resistance	R _{DS(on)}	-	0.39	0.45	Ω	V _{GS} =10V, I _D =5.5A, T _j =25°C T _j =150°C
Transconductance	g _f	-	12	-	S	V _{DS} =20V, I _D =5.5A

Dynamic Characteristic

Input Capacitance	C _{iss}	-	790	-	pF	V _{GS} =0V, V _{DS} =100V, f=1MHz
Output Capacitance	C _{oss}	-	32	-		
Reverse Transfer Capacitance	C _{rss}	-	2	-		
Gate Total Charge	Q _G	-	22	-	nC	V _{GS} =10V, V _{DS} =480V, I _D =5.5A
Gate-Source charge	Q _{gs}	-	5.3	-		
Gate-Drain charge	Q _{gd}	-	8.8	-		
Turn-on delay time	t _{d(on)}	-	20	-		
Rise time	t _r	-	15	-		
Turn-off delay time	t _{d(off)}	-	74	-	ns	T _j =25°C, V _{GS} =10V, I _D =5.5A, V _{DS} =400V, R _g =25Ω
Fall time	t _f	-	43	-		
Gate resistance	R _G	-	2.0	-		



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Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V_{SD}	0.5	0.84	1	V	$V_{GS}=0V, I_{SD}=5.5A$
Body Diode Reverse Recovery Time	t_{rr}	-	218	-	ns	$I_{sd}=5.5A$ $dI/dt=100A/\mu s$ $V_{ds}=100V$
Body Diode Reverse Recovery Charge	Q_{rr}	-	2.35	-	μC	

Typical Performance Characteristics

Fig 1. Output Characteristics ($T_j=25^\circ\text{C}$)

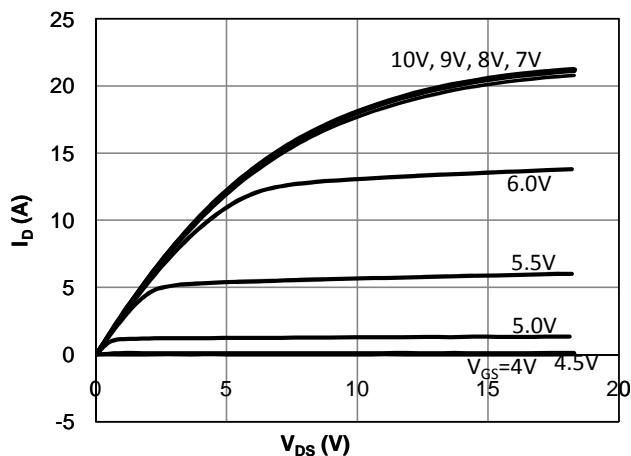


Fig 2. Output Characteristics ($T_j=150^\circ\text{C}$)

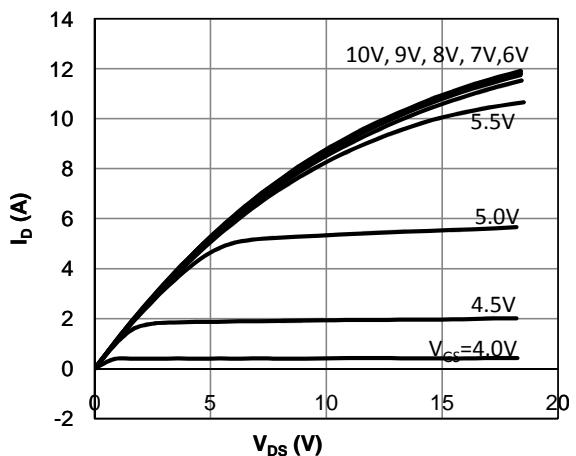


Fig 3: Transfer Characteristics

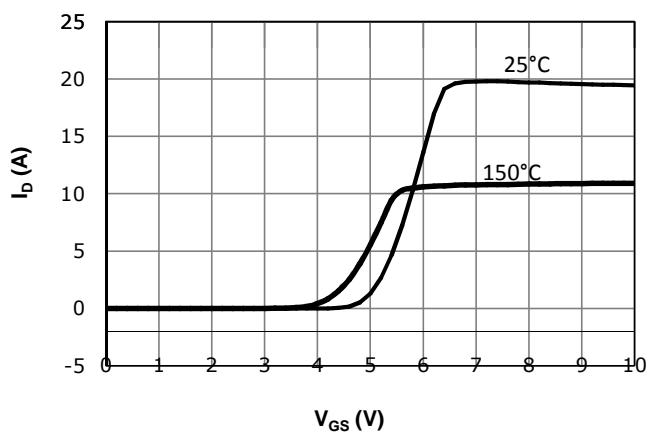


Fig 4: V_{TH} Vs T_j Temperature Characteristics

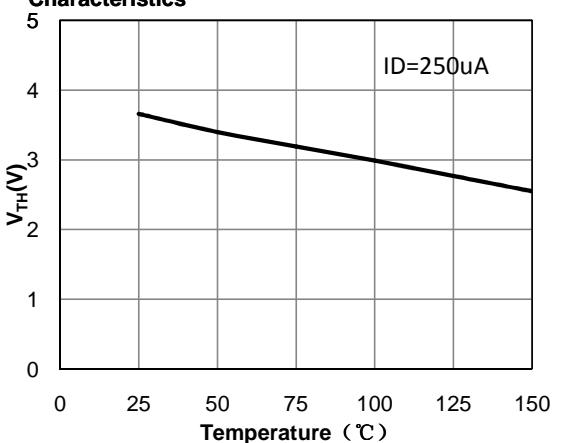


Fig 5: $R_{DS(on)}$ Vs I_{DS} Characteristics ($T_c=25^\circ\text{C}$)

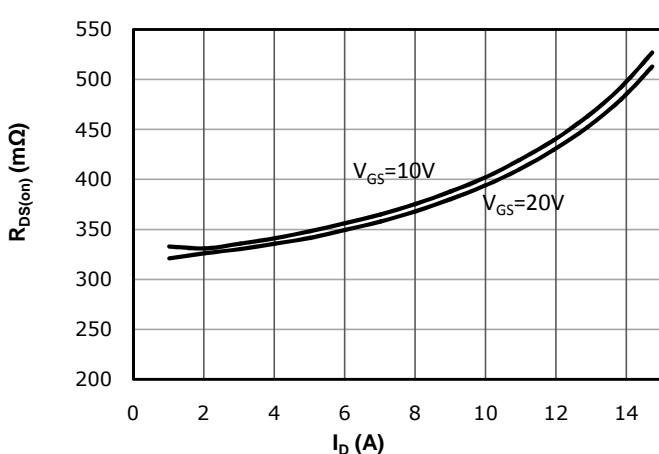


Fig 6: $R_{DS(on)}$ vs. Temperature

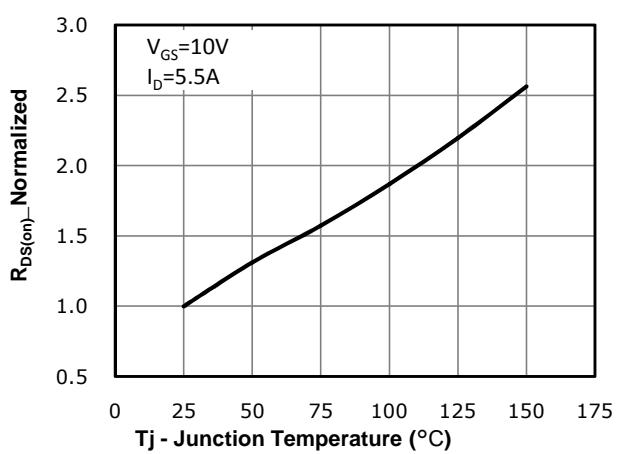


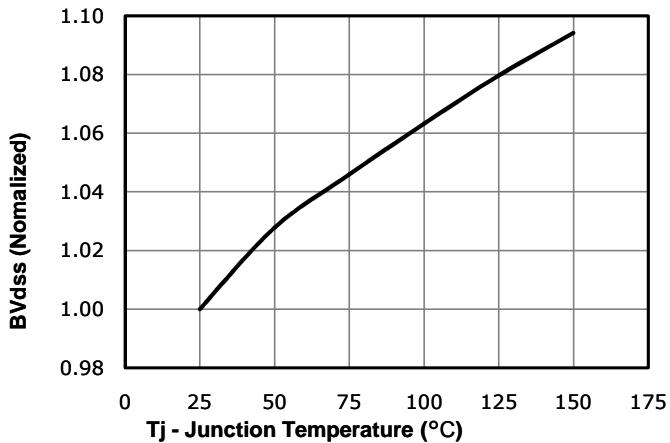
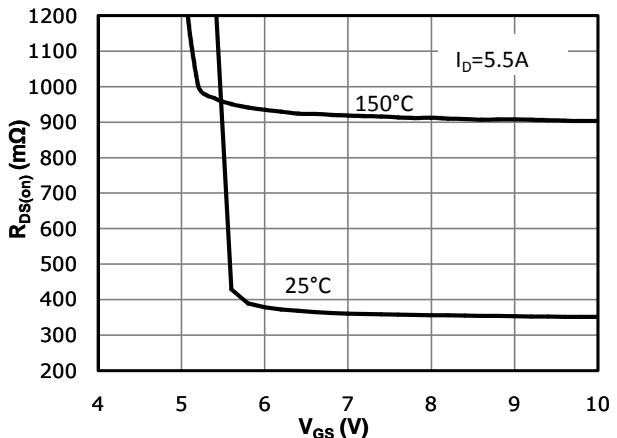
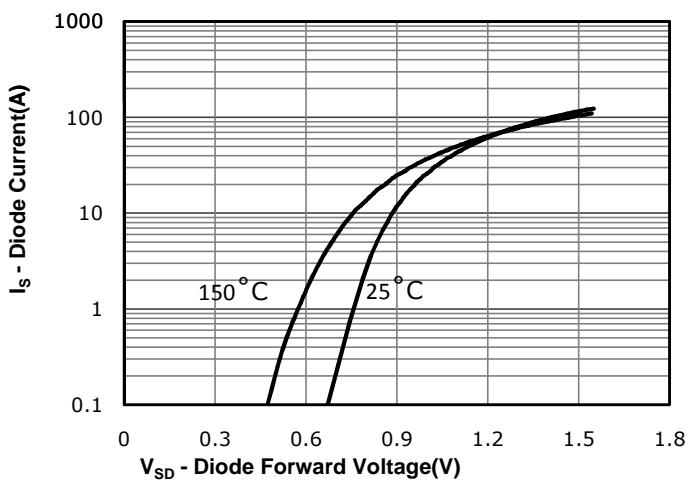
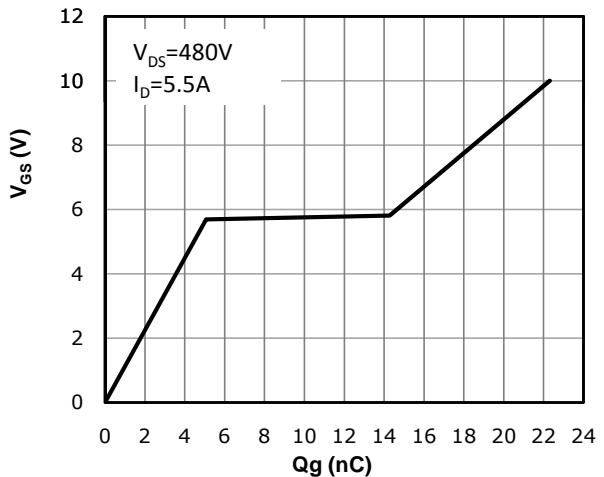
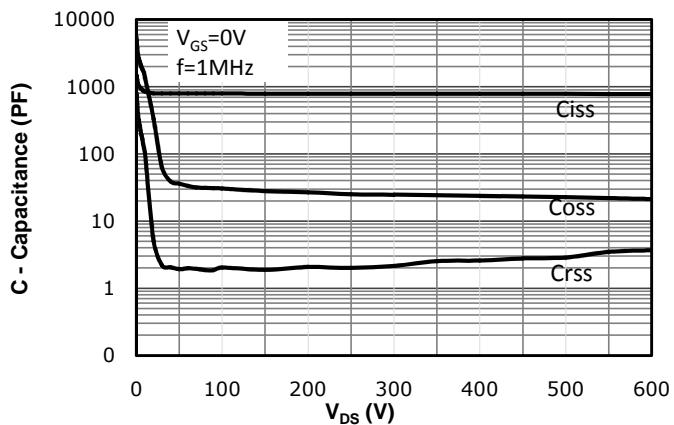
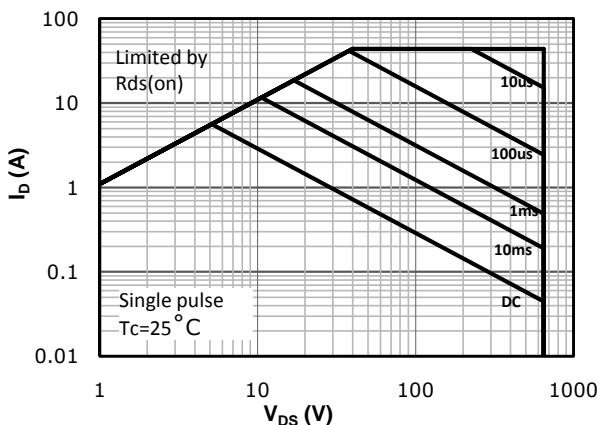
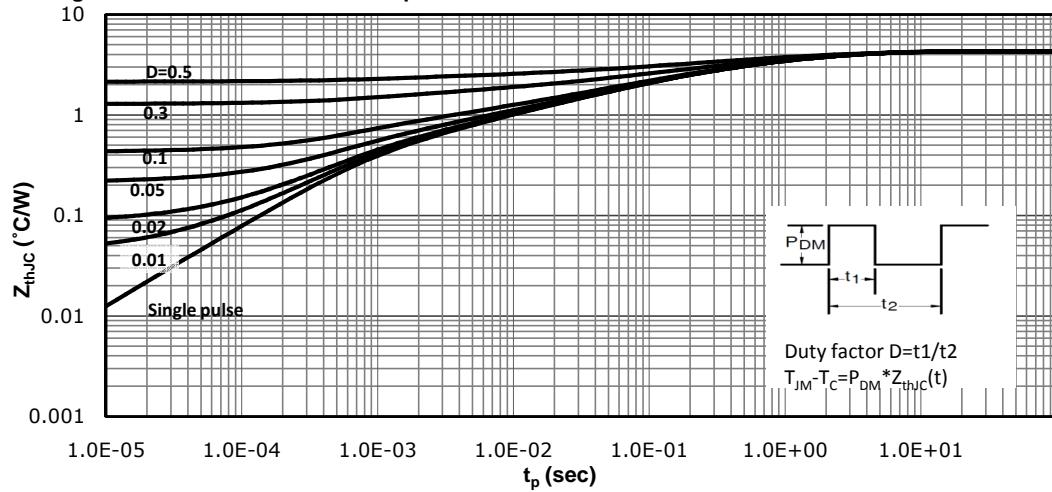
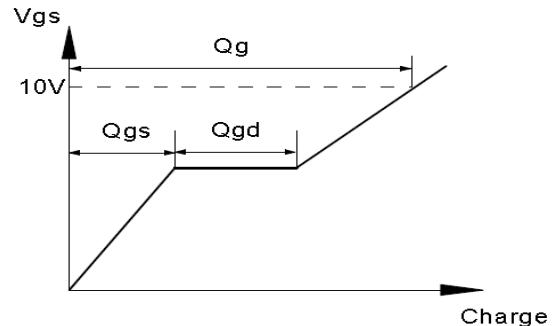
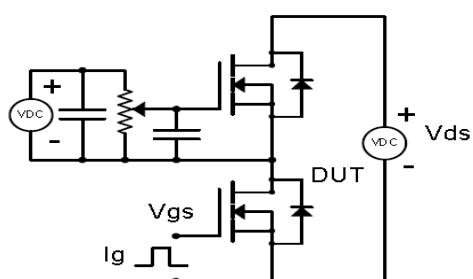
Fig 7: BV_{DSS} vs. Temperature

Fig 8: R_{d(on)} vs Gate Voltage

Fig 9: Body-diode Forward Characteristics

Fig 10: Gate Charge Characteristics

Fig 11: Capacitance Characteristics

Fig 12: Safe Operating Area


Fig 13: Max. Transient Thermal Impedance

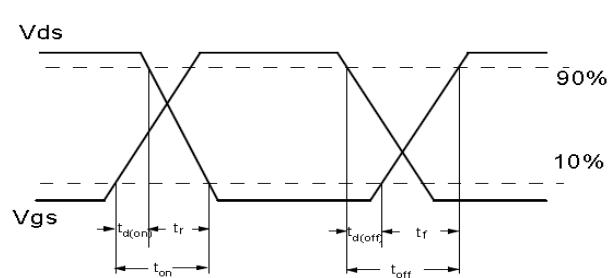
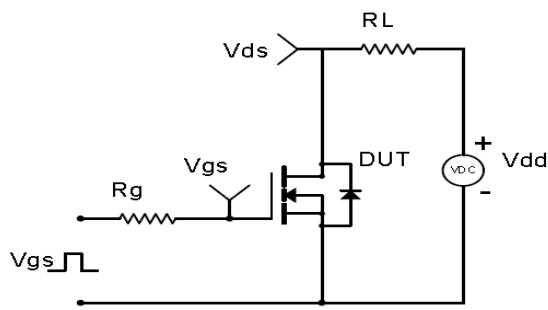


Test Circuit & Waveform

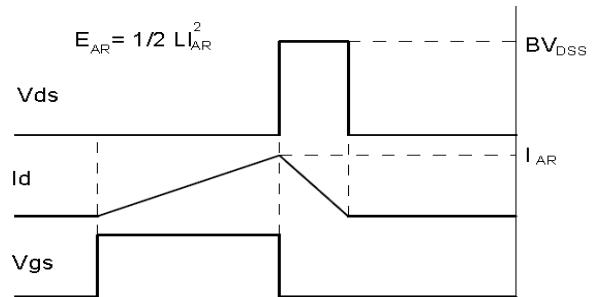
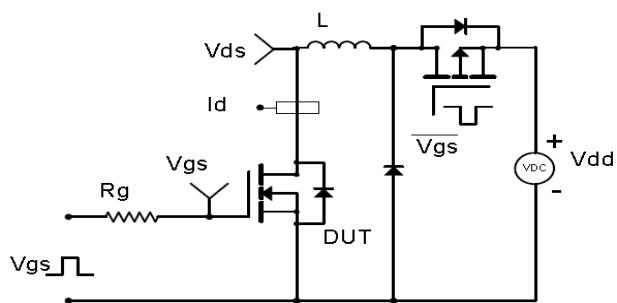
Gate Charge Test Circuit & Waveform



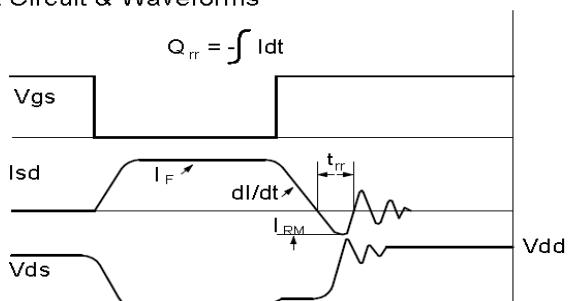
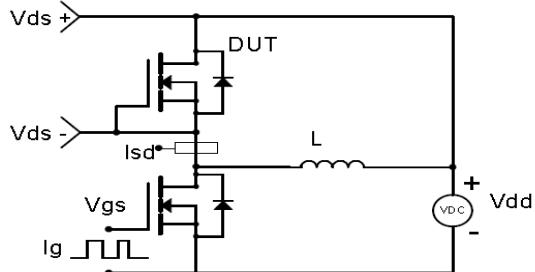
Resistive Switching Test Circuit & Waveforms

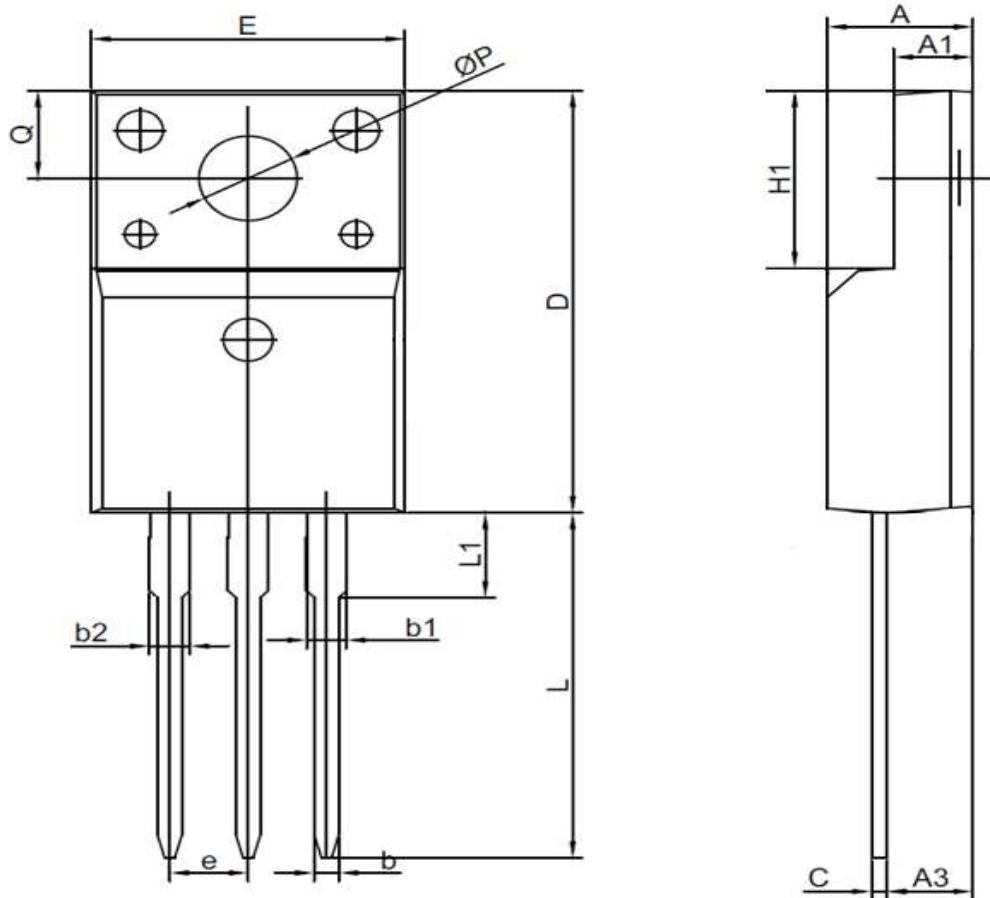


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Package Outline: TO-220F


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.30	4.90	0.169	0.193
A1	2.34	2.87	0.092	0.113
A3	2.20	2.96	0.087	0.117
b	0.60	0.90	0.024	0.035
b1	0.95	1.45	0.037	0.057
b2	1.15	1.55	0.045	0.061
c	0.40	0.70	0.016	0.028
D	15.50	16.17	0.610	0.637
e	2.54 BSC		0.100 BSC	
E	9.70	10.66	0.382	0.420
H1	6.70 REF		0.264 REF	
L	12.46	13.75	0.491	0.541
L1	2.80	3.80	0.110	0.150
Q	3.05	3.55	0.120	0.140
P	2.98	3.38	0.117	0.133

Marking



NOTE:
NXBBAAAAY
X —Assembly location code
BB —Fab code
AAAA —Lot code
Y —Bin code

Revision History

Revison	Date	Major changes
1.0	2019-8-13	Release of formal version
1.1	2021-2-3	Update Ptot
1.2	2021-4-29	Update Package Outline
2.0	2022-4-26	Update Cxss and package outline; Add MOSFET dv/dt ruggedness, Recovery diode dv/dt, Continuous diode forward current, Diode pulse current; 增加电气引脚描述

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.

CRM(CQ) reserves the right to improve product design, function and reliability without notice.